# N-channel TrenchMOS intermediate level FET Rev. 1 — 18 August 2010

Product data sheet

#### **Product profile** 1.

#### 1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

#### 1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources

#### **1.3 Applications**

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

### 1.4 Quick reference data

#### Table 1 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Parameter	Conditions		Min	Тур	Max	Unit
drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	120	A
total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	306	W
aracteristics						
drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>		-	2	2.3	mΩ
	drain-source voltage drain current total power dissipation aracteristics drain-source on-state	$\begin{array}{ll} \mbox{drain-source} & T_j \geq 25 \ {}^\circ\mbox{C}; \ T_j \leq 175 \ {}^\circ\mbox{C} \\ \mbox{voltage} & \\ \mbox{drain current} & V_{GS} = 10 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; \\ \mbox{see Figure 1} \\ \mbox{total power} & \\ \mbox{dissipation} & \\ \mbox{aracteristics} \\ \mbox{drain-source} & V_{GS} = 10 \ V; \ I_D = 25 \ A; \\ \mbox{on-state} & T_j = 25 \ {}^\circ\mbox{C}; \ see Figure 11; \\ \end{array}$	$\begin{array}{ll} \mbox{drain-source} & T_j \geq 25 \ {}^\circ\mbox{C}; \ T_j \leq 175 \ {}^\circ\mbox{C} \\ \mbox{voltage} & \\ \mbox{drain current} & V_{GS} = 10 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; & \mbox{[1]} \\ \mbox{see} \ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $	$\begin{array}{c} drain-source \\ voltage \\ drain current \\ total power \\ dissipation \\ \end{array} \begin{array}{c} T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} \\ \text{see } Figure 1 \\ \hline \\ total power \\ \text{dissipation} \\ \end{array} \begin{array}{c} 11 \\ \text{see } Figure 1 \\ \hline \\ \text{mb} = 25 \ ^{\circ}\text{C}; \ \text{see } Figure 2 \\ \text{drain-source} \\ \text{on-state} \\ \hline \\ T_{j} = 25 \ ^{\circ}\text{C}; \ \text{see } Figure 11; \\ \hline \end{array}$	$\begin{array}{c} \text{drain-source} & T_j \geq 25 \ ^\circ\text{C}; \ T_j \leq 175 \ ^\circ\text{C} & - & - \\ \text{voltage} & \text{drain current} & \text{V}_{\text{GS}} = 10 \ \text{V}; \ T_{\text{mb}} = 25 \ ^\circ\text{C}; & \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $	$\begin{array}{cccc} drain-source & T_j \geq 25 \ ^\circ C; \ T_j \leq 175 \ ^\circ C & - & - & 40 \\ drain \ current & V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^\circ C; & 11 & - & - & 120 \\ see & Figure \ 1 & & & \\ total \ power & T_{mb} = 25 \ ^\circ C; \ see & Figure \ 2 & - & - & 306 \\ dissipation & & & \\ \hline aracteristics & & & \\ drain-source & V_{GS} = 10 \ V; \ I_D = 25 \ A; & - & 2 & 2.3 \\ on-state & T_j = 25 \ ^\circ C; \ see & Figure \ 11; & & & \\ \end{array}$



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Table 1.	Quick reference da	tacontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 120 \text{ A};  \text{V}_{\text{sup}} \leq 40 \text{ V}; \\ R_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 10 \text{ V}; \\ T_{\text{j(init)}} &= 25 ^{\circ}\text{C}; \text{ unclamped} \end{split} $	-	-	1.02	J
Dynamic	characteristics					
Q <sub>GD</sub>	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \underline{Figure 13};$ $\text{see } \underline{Figure 14}$	-	72	-	nC

[1] Continuous current is limited by package.

### 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	Drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT226 (I2PAK)	

### 3. Ordering information

Table 3. Ordering	g information		
Type number	Package		
	Name	Description	Version
BUK6E2R3-40C	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

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### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>GS</sub>	gate-source voltage	DC	<u>[1]</u>	-16	16	V
		Pulsed	[2]	-20	20	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see Figure 1	[3]	-	120	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see Figure 1	[3]	-	120	А
I <sub>DM</sub>	peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed};$ see Figure 3		-	1006	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	306	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drai	n diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[3]	-	120	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	1006	А
Avalanche r	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ld} \begin{array}{l} I_D = 120 \; A; \; V_sup \leq 40 \; V; \; R_GS = 50 \; \Omega; \\ V_GS = 10 \; V; \; T_j(init) = 25 \; ^\circ C; \; unclamped \end{array}$		-	1.02	J
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy		[4][5][6]	-	-	J

[1] -16V accumulated duration not to exceed 168 hrs

[2] Accumulated pulse duration not to exceed 5mins.

[3] Continuous current is limited by package.

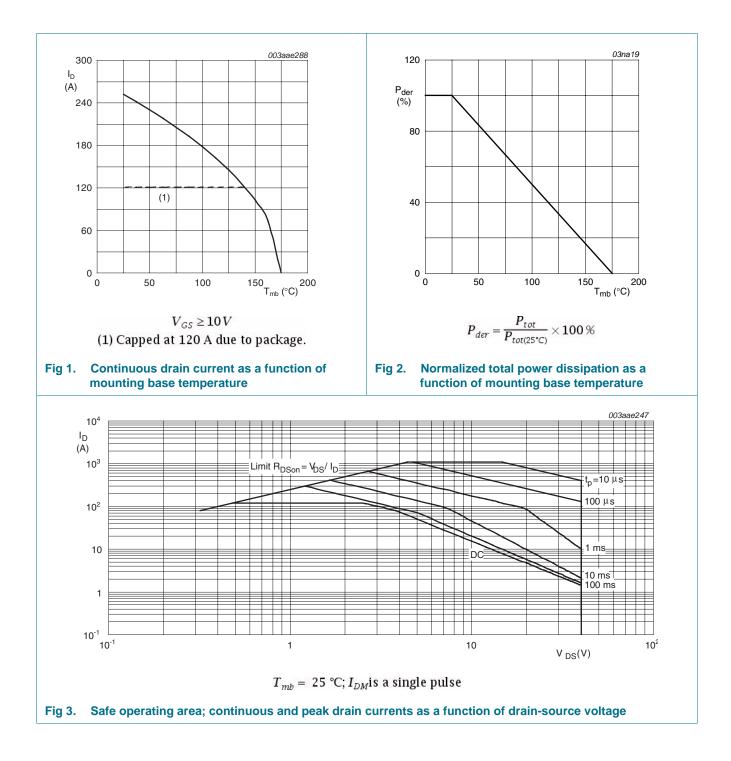
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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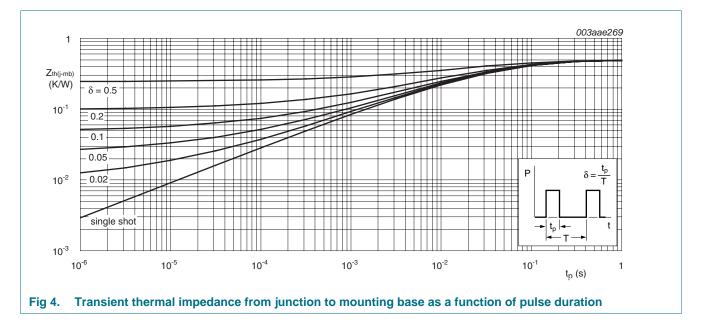
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### 5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see <mark>Figure 4</mark>	-	-	0.49	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W



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### 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Static cha	racteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	40	-	-	V
	breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 10</u>	-	-	3.3	V
		$I_D = 2.5 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 10</u>	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = 20 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
		V <sub>DS</sub> = 0 V; V <sub>GS</sub> = -20 V; T <sub>j</sub> = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2	2.3	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2.5	3.1	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2.8	3.6	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; see <u>Figure 11</u>	-	-	5	mΩ
Dynamic o	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14	-	260	-	nC
		$I_D = 25 A$ ; $V_{DS} = 32 V$ ; $V_{GS} = 5 V$ ; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	147	-	nC
Q <sub>GS</sub>	gate-source charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 32 V; V <sub>GS</sub> = 10 V;	-	38	-	nC
Q <sub>GD</sub>	gate-drain charge	see Figure 13; see Figure 14	-	72	-	nC
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	11.3	15.1	nF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	1447	1750	pF
C <sub>rss</sub>	reverse transfer capacitance		-	1014	1390	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	60	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega$	-	140	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	234	-	ns
t <sub>f</sub>	fall time		-	416	-	ns
L <sub>D</sub>	internal drain inductance	from drain lead 6 mm from package to centre of die; T <sub>j</sub> = 25 °C	-	4.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bond pad; $T_i = 25 ^{\circ}\text{C}$	-	7.5	-	nH

Symbol

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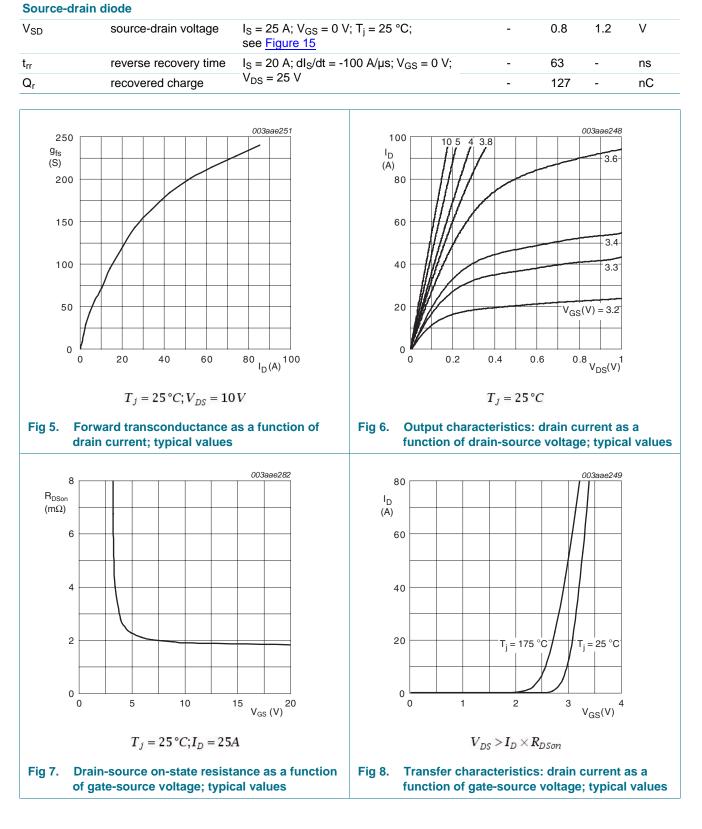
Max

Тур

Unit

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Min



#### Table 6. Characteristics ...continued

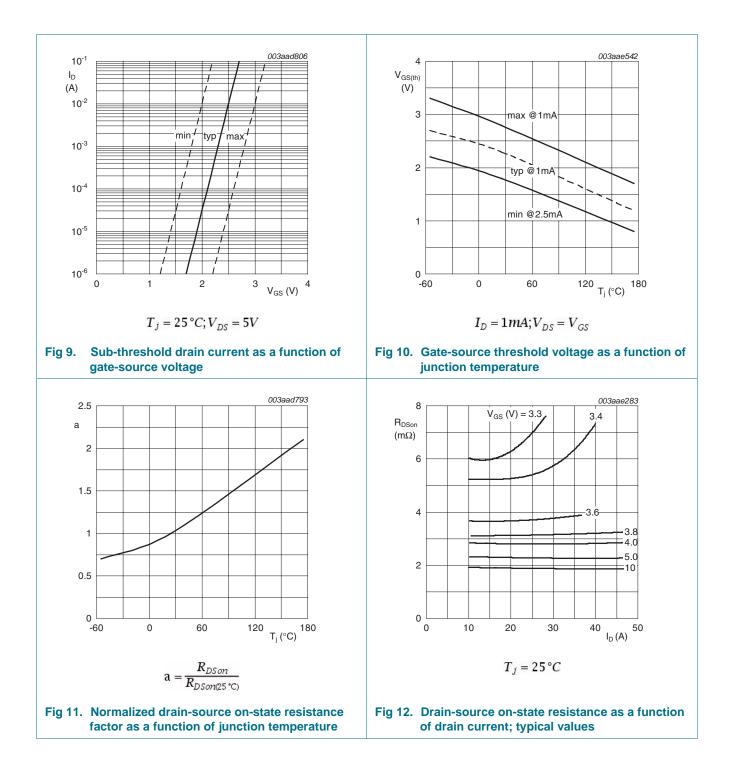
Parameter

Conditions

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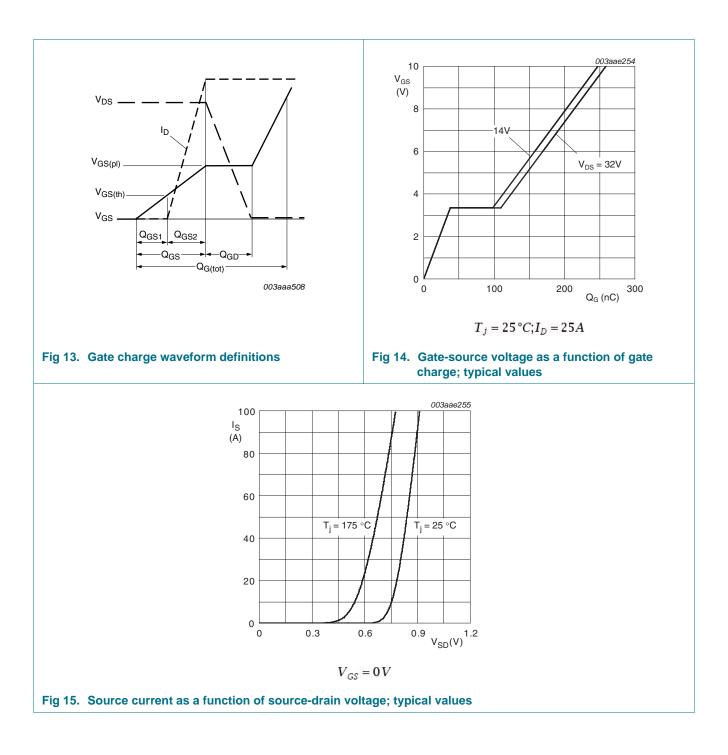
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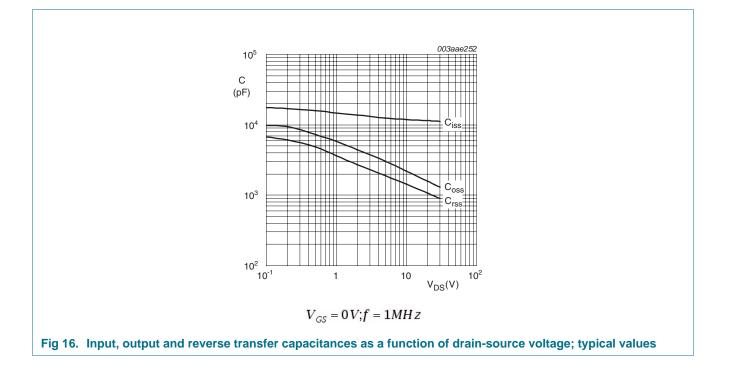
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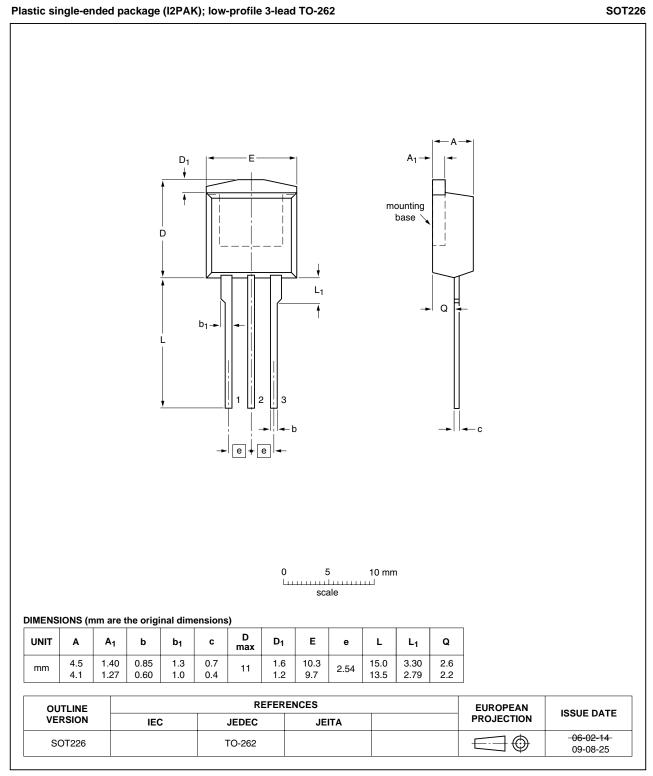
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### 7. Package outline



#### Fig 17. Package outline SOT226 (I2PAK)

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### 8. Revision history

Table 7. Revision h	e 7. Revision history						
Document ID	Release date	Data sheet status	Change notice	Supersedes			
BUK6E2R3-40C v.1	20100818	Product data sheet	-	-			

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Document status[1][2]	Product status <sup>[3]</sup>	Definition
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